[ZnO-07]

Intentional Hydrogen Doping of Polycrystalline ZnO Thin Film Using Photo-MOCVD Technique

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The effect of hydrogen doping on polycrystalline ZnO thin film prepared by a metalorganic chemical vapor deposiont (MOCVD) technique has been investigated. From the increased electrical conductivity and improved electrical stability under air atmosphere [1–2], we speculated that the substitutional complex consisting of an oxygen vacancy and a hydrogen atom as well as interstitial hydrogen located between O–Zn bonds acts as shallow donors [3–4] and decreases oxygen vacancies. Besides the intentional hydrogen incorporation process improves the surface texture.

[Reference]

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